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Ujjwal Guin is currently an Assistant Professor in the Department of Electrical and Computer Engineering, Auburn University. He received his Ph.D. degree from the University of Connecticut in 2016. He is actively involved in Hardware Security and Trust, Supply Chain Security, Cybersecurity, and VLSI Design and Test projects. He has developed several on-chip structures and techniques to improve integrated circuit security, trustworthiness, and reliability. He is a co-author of the book, *Counterfeit Integrated Circuits: Detection and Avoidance*. He has authored several journal articles and refereed conference papers. His projects are sponsored by the United States Secret Service, National Science Foundation (NSF), Air Force Research Laboratory (AFRL), and Auburn University. He serves on the SAE International G-19A Test Laboratory Standards Development Committee and G-32 Cyber-Physical Systems Security Committee. He currently serves or has served on technical program committees of reputed conferences, such as, DAC, HOST, VTS, PAINE, VLSID, GLSVLSI, ISVLSI and Blockchain. He is a Senior Member of IEEE and a Member of ACM.
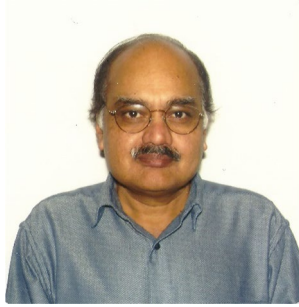
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He cofounded the IEEE International Workshop on IDDQ Testing in 1995 (later known as DBT) and served as its first General Chair. He has contributed the concepts of Detectability Profile (1984), Antirandom testing (1995), Coverage based defect detection model (1994) and the Alhazmi-Malaiya (AML) Vulnerability Discovery Model (2005). His Antirandom testing paper was included in "Most Influential Papers - The 30 Years of ISSRE" in 2019. His 1980 paper on delay faults was selected for the "25th Anniversay Compendium of papers" from the International Test Conference, 1994. He co-edited the IEEE CS Technology Series books "Software Reliability Models, Theoretical Developments, and Evaluation and Applications" in 1990, and "Bridging Faults and IDDQ Testing" in 1992. He served as the chair of IEEE-CS Technical Committee on Microprogramming and Microarchitecture (1988-92), and a member of executive committee of the IEEE CS Technical Activities Board (1988-98) and Conference and Tutorials Board (1994, 2000, and 2001). He has supervised PhD and MS students in Computer Science, Electrical Engineering and Systems Engineering. He has served in ABET for accreditation of Computer Science programs in USA and overseas. He has developed and taught new courses in Fault-tolerant Computing and Quantitative Security. Dr. Malaiya is a recipient of the IEEE Third Millennium Medal and the IEEE Computer Society Golden Core Award.